

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Substitute for form 1449/PTO)

ATTY. DOCKET NO.
044117-0143

SERIAL NO.
10/539,771

APPLICANT
Eric PINET, et al.

FILING DATE
January 10, 2006

GROUP
1797

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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/Samuel Siefke/

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